

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

Substitute for form 1449A/PTO

Sheet 1 of 3
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Complete if Known
Applicant Number NEW APPLICATION
Filing Date HEREWITH
First Named Inventor Oh-Hun Kwon, et al.
Group Art Unit
Examiner Name
Attorney Docket Number 1035-PM4034-DIV

10/689192

U.S. PATENT DOCUMENTS

Examiner Initials *	Cite No. 1	U.S. Patent Document Number	Kind Code 2 (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
	AA	2,528,121		Dickinson	05/20/1948	
	AB	3,502,597		Bush	03/24/1970	
	AC	4,110,260		Yamamoto, et al.	08/29/1978	
	AD	4,316,964		Lange	02/23/1982	
	AE	4,931,214		Worrell, et al.	06/05/1990	
	AF	5,612,144		Aida, et al.	09/28/1999	
	AG	5,830,819		Shikata, et al.	11/03/1998	
	AH	5,958,813		Shinohara, et al.	03/18/1997	
	AI	6,136,232		Burlingame	10/24/2000	
	AJ	4,820,666		Hirano, et al.	04/11/1989	

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	AK	JP	3-5363			01/11/1999		<input type="checkbox"/>
	AL	DE	3743630			03/16/1989		<input type="checkbox"/>
	AM	JP	62-025404	A		08/12/1994		<input type="checkbox"/>
	AN	JP	8-039441		Hideharu Hasegawa	02/13/1996		<input type="checkbox"/>
	AO	JP	10-296646	A	Hiroshi Hamashima	11/10/1998		<input type="checkbox"/>

PUBLICATIONS

Examiner Initials *	Cite No. 1	Title of Publication	Date of Publication of Cited Document MM-DD-YYYY
	AW	A.J. Wallash, "Electrostatic Discharge (ESD) in Magnetic Recording: Past, Present and Future," Proc. of Understanding ESD in Magnetic Recording, IDEMA, pp. 3-20, 2000.	
	AX	A.J. Wallash, et al., "ESD Failure Mechanisms of Inductive and Magneto-resistive Recording Heads," EOD/ESD Symposium 95, pp. 322-330 (1995).	
	AY	J. Elston, et al., "Study of High-temperature Electrical Properties of Zirconia and Lanthanum Chromite Sinisters," Proceedings of a Symposium on Magnetohydrodynamic Electrical Power Generation, P. 1061, 389-403, 1966.	
	AZ	C. Lam, "Characterization of ESD Tweezers for Use with Magneto-resistive Recording Heads," EOS/ESD Symposium -1996, pp. 14-21 (1996)	

Examiner Signature		Date Considered	3/28/2005
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

1 Unique citation designation number. 2 See attached Kinds of U.S. Patent Documents. 3 Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). 4 For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. 5 Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. 6 Applicant is to place a check mark here if English language Translation is attached.

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	BA	3,410,728		Fullman, et al.	06/10/1965	
	BB	6,274,524		Mikaki, et al.	08/14/2001	
	BC	6,069,103		Kwon, et al.	05/30/2000	
	BD	6,379,529		Wahl, et al.	04-2002	
	BE	6,258,233		Sugiyama, et al.	07-2001	
	BF	6,232,004		Lasater	05-2001	
	BG	6,039,221		Chatterjee, et al.	03-2000	
	BH	5,800,934		Quadri, et al.	09-1998	
	BI	5,175,132		Ketcham, et al.	12-1992	
	BJ	4,035,191		Johns	07/1977	

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	BK	WO	98/49121		Shunji Mikaki	11/05/1998		<input type="checkbox"/>
	BL							<input type="checkbox"/>
	BM							<input type="checkbox"/>
	BN							<input type="checkbox"/>
	BO							<input type="checkbox"/>

PUBLICATIONS

Examiner Initials *	Cite No.1	Title of Publication	Date of Publication of Cited Document MM-DD-YYYY
	BW	K.J. Kim, et al., "Advancements in Inherently Dissipative Polymer (IDP) Alloys Provide New Levels of Clean, Consistent ESD Protection," EOS/ESD Symposium 2000, pp. 132-38, 2000.	
	BX	R.V. Wilhelm, D.S. Howarth, "Iron Oxide-doped Ytria-Stabilized zirconia Ceramic: Iron Solubility and Electrical Conductivity," Am. Ceram. Soc. Bull., 58 (2) 228-32 (1979).	
	BY	N.A. Pratten, "Review, The Precise Measurement of the Density of Small Samples," J. Mater. Sci., 16, 1737-47 (1981).	
	BZ	ASTM: D257-93, "Standard Test Methods for DC Resistance or Conductance of Insulating Materials," pp. 108-124.	

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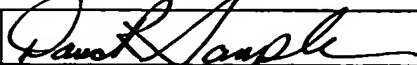
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	AAA	FED. Test Method Std. No. 101, "Electrostatic Properties of Materials," Rev. B, Method 4046, Jan. 1969; Rev. C, Method 4046.1, Oct. 1982, Change Notice 1.	
	AAB	N. Jonassen, "Static-Electric Characterization of Semi-insulating Materials," EOS/ESD Symposium EOS-6, pp. 45-49, 1984.	
	AAC	G. Baumgartner, "Electrostatic Decay Measurement, Theory and Applications," EOS/ESD Symposium 95, pp. 262-72, 1995.	
	AAD	C.F.Lam, et al., "Decay-Time Characterization of ESD Materials for Use with Magnetoresistive Recording Heads," EOS/ESD Symposium 97, pp. 373-81, 1997.	
	AAE	M.J. DeBarr, et al., "Conduction Mechanism in the La(Al,Mn) ₃ System," Point Defects and Related Properties of Ceramics, ED. T.O. Mason, et al., Ceramic Trans., Vol. 24, am. Ceram. Soc., pp. 229-238, 1991.	
	AAF	M.S. Islam, et al., "Defect Chemistry of LaBO ₃ (B= La, Mn or Co) Perovskite-type Oxides," J. Chem. Soc., Faraday trans, 92930 479-482 (1996).	
	AAG		
	AAH		
	AAI		
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	AAK		
	AAL		
	AAM		
	AAN		
	AAO		
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